

Low Power Front End for the Optical Module of a Neutrino Underwater Telescope

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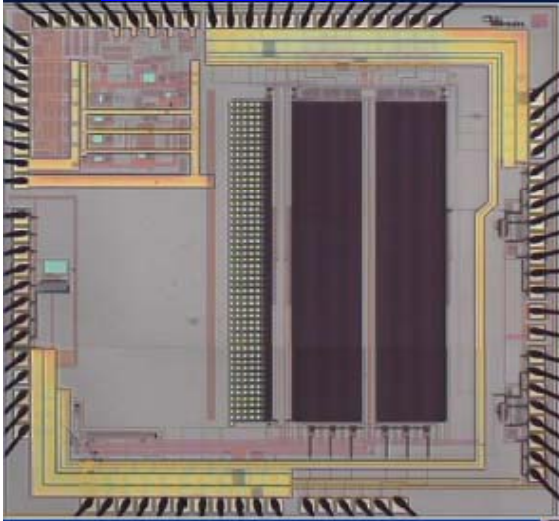
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Summary

- Front end electronics for a Km³ submarine neutrino detector:
 - LIRA chip
 - Test of the first prototype of the Front-end using LIRA chip (CT-BO) **see F. Giorgi talk**
 - Study and design of the new front-end
 - Specifications
 - Architecture
 - Status of work

LIRA Chip

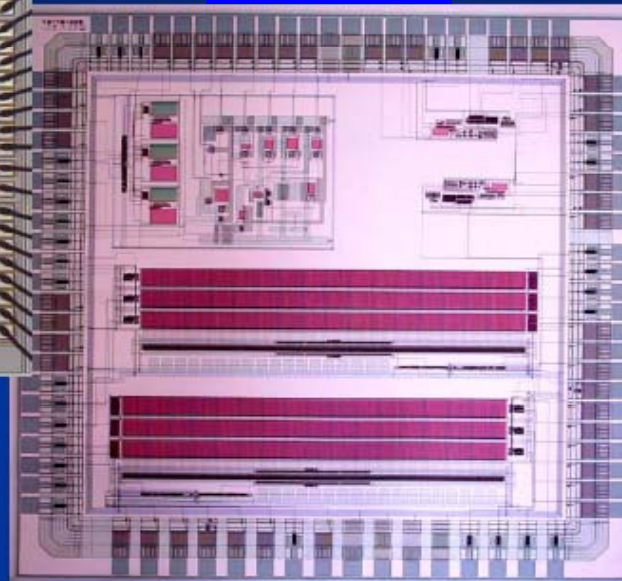
LIRA03



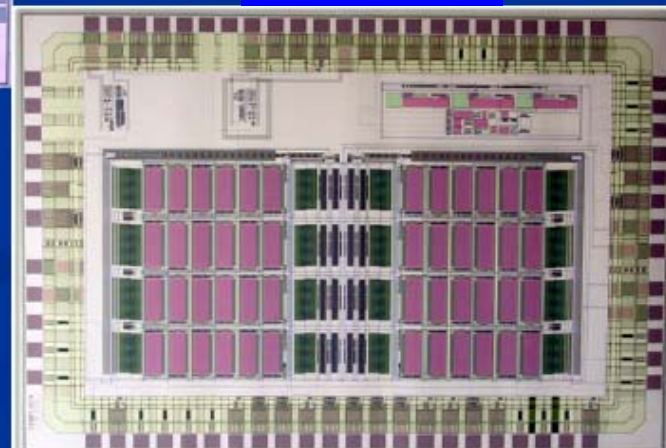
LIRA01 and LIRA02

Not Submitted to foundry

LIRA04



LIRA05



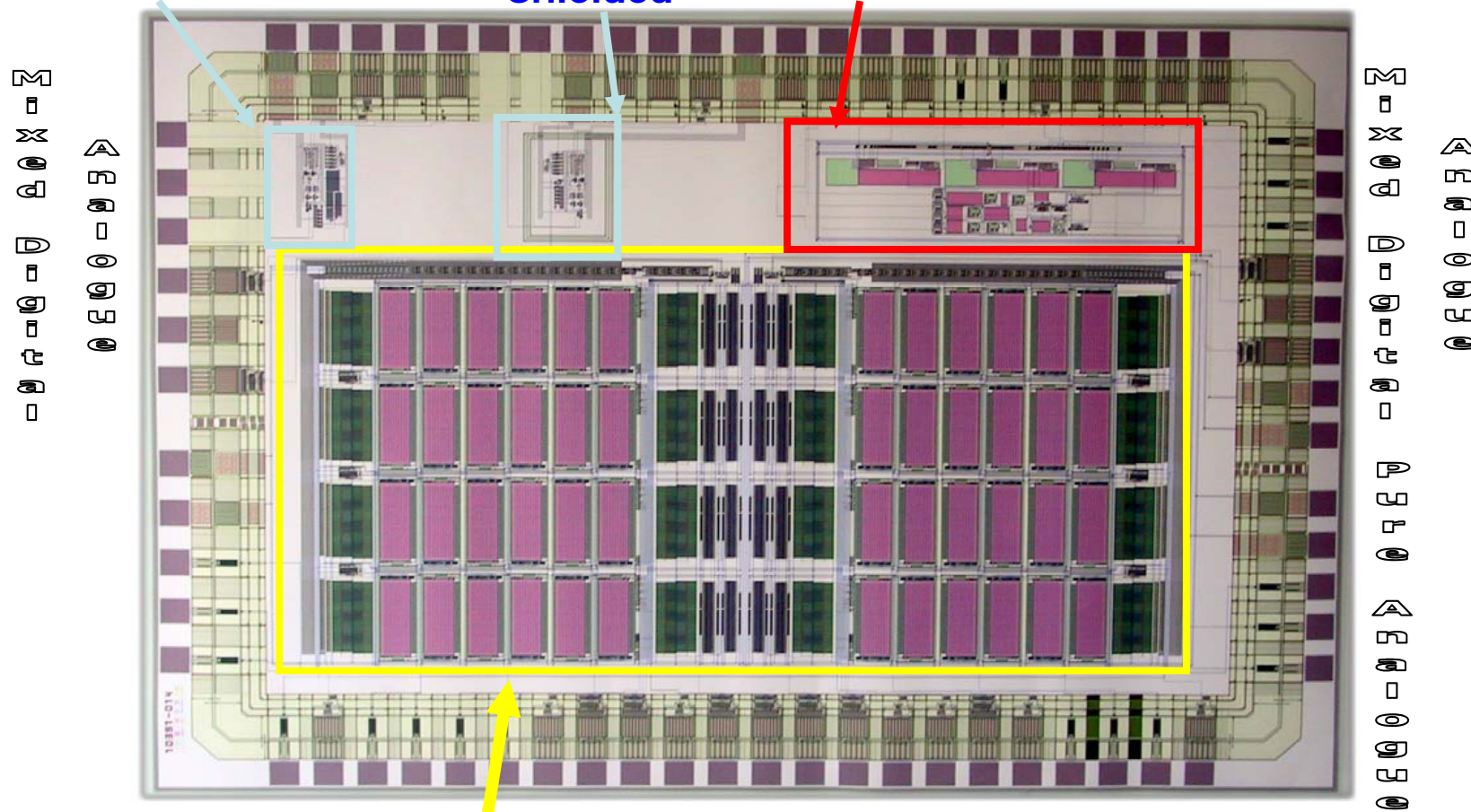
AMS 0,35 μm CMOS Technology

Europractice MPW

PLL Stand Alone 400 MHz
Slave Clock Generator

LIRA's PLL
Shielded

Trigger and Single
Photon Classifier TSPC



2 AM 200 MHz Write 10 MHz Read
LIRA05 CHIP CMOS 0,35 μm AMS technology

LIRA Chip

- 2 SCA 3 ch.x256 cells working alternatively in read and write mode to reduce dead time
 - 200 MHz sampling 10 MHz transfer
 - 9 bit resolution
 - Anode and last dynode sampled (double linear dynamic)
 - 20 MHz master clock sampled for time stamp
- Trigger and Single Photon Classifier
 - 3 5-bit DAC with slow control interface
- PLL to produce 200 MHz on chip
- 120 mW total power dissipation!!

Front end using LIRA chip

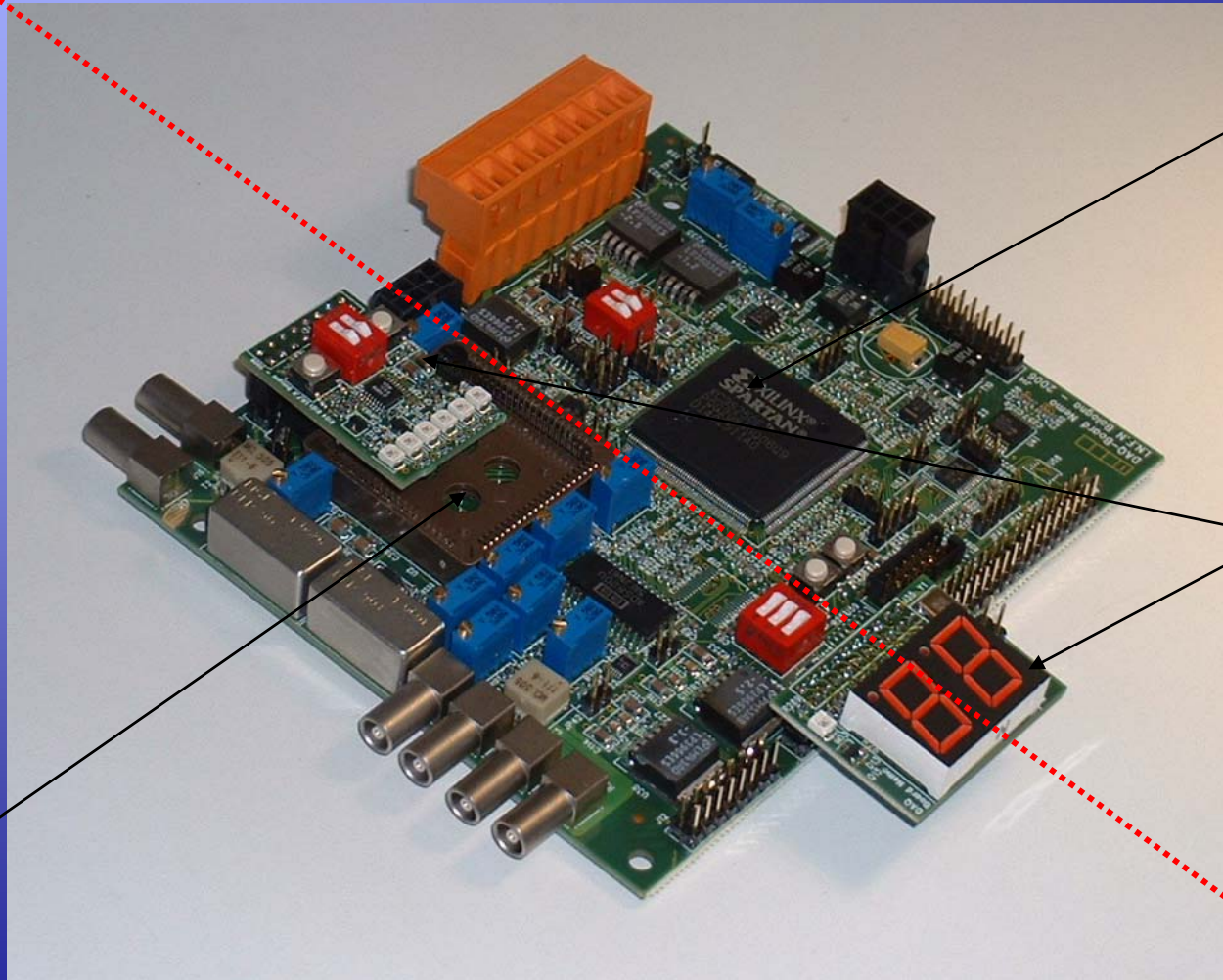
ANALOG

FPGA
Spartan 3E

Mezzanine di
debug

Socket chip
LIRA

DIGITAL



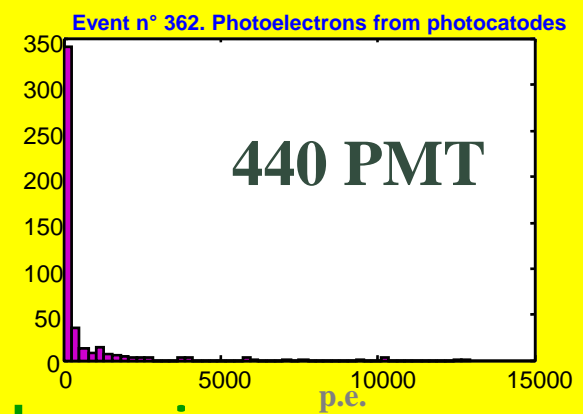
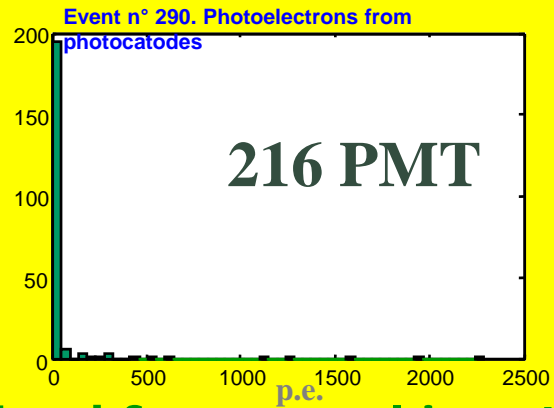
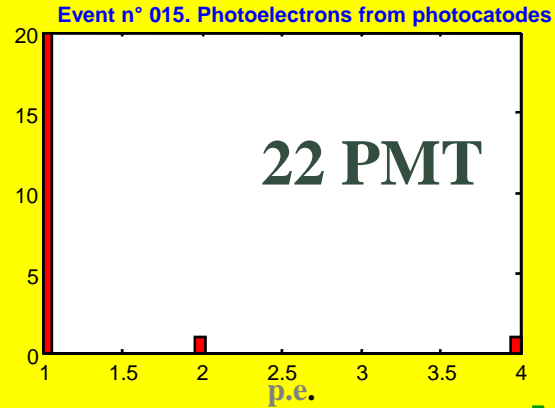
See F. Giorgi talk

Simulations

- High energy neutrino events in NEMO detector
- ^{40}K spe background
- Seawater Optical properties
- Optical module spacing, orientation and position
- Hits in each pmt of the detector in presence of an event

Charge Dynamics

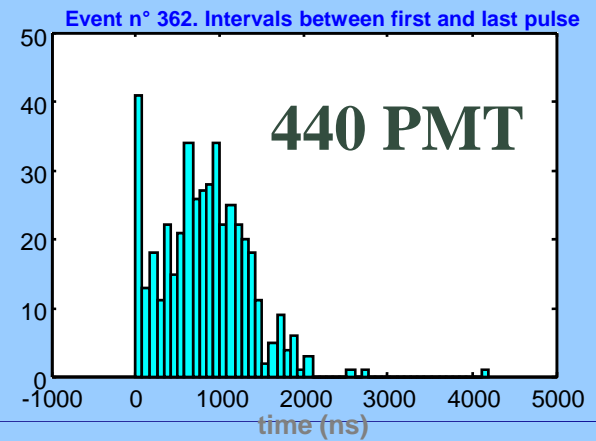
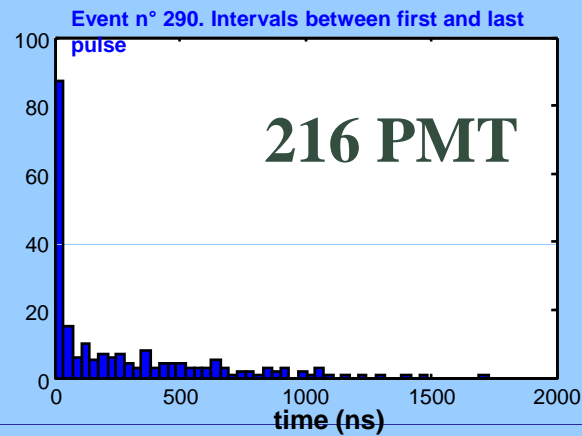
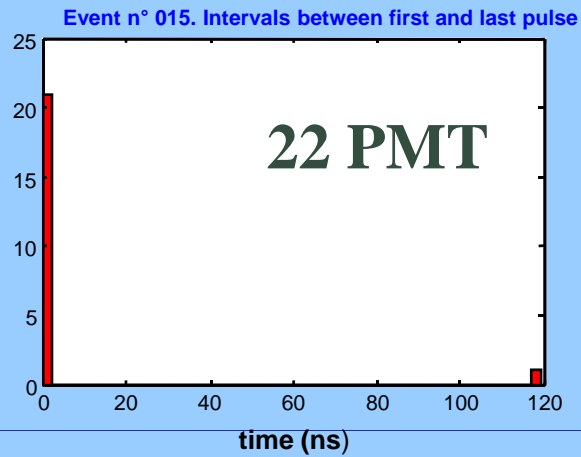
p.e. spectra of three typical high energy neutrino events



Need for several input dynamics

Time Dynamics

Maximum signals length spectra of three typical high energy events

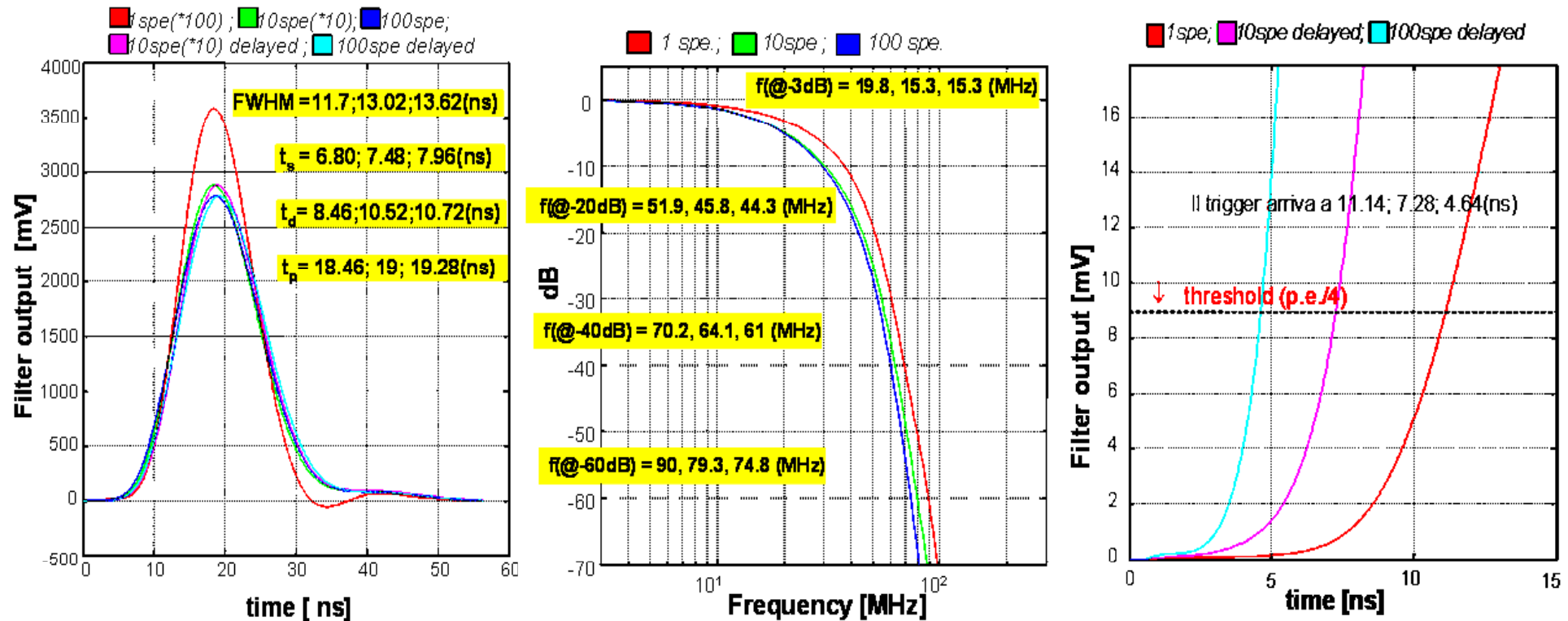


Specialized Samplers

Study and Design of the Front-End Electronics

- Simulation of neutrino events in a realistic detector (NEMO like)
- Simulation of the real Optical Module response
- Optimal Signal Filtering
- Simulation of the Front-End chain with realistic performances
- Evaluation of the detector performances as regards to acquisition parameters
- Considerations on Power Dissipation and data flow
- ASIC design

Filtered PMT Signal



Typical filtered signals (1, 9.3 and 94 p.e.).

A $\frac{1}{4}$ p.e. threshold gives a fluctuation of about 7 ns. We foresee to sample 2-3 leading edge zeros and 2-3 trailing edge zeros. Signals must be delayed respect to trigger with a delay line.

The filter is necessary to avoid aliasing at 200Msample/sec.

Signals measured with $\text{PMT}_{\text{gain}} = 5 \cdot 10^7$. PMT works not linearly for high photons levels.

It is useful to reduce the PMT gain to achieve a greater linear dynamics.

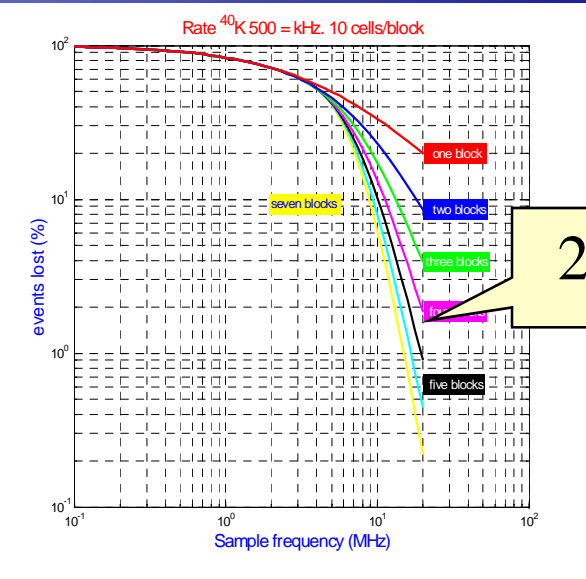
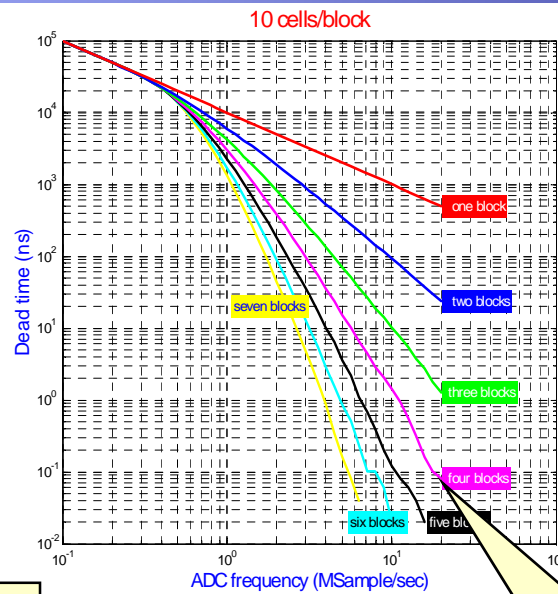
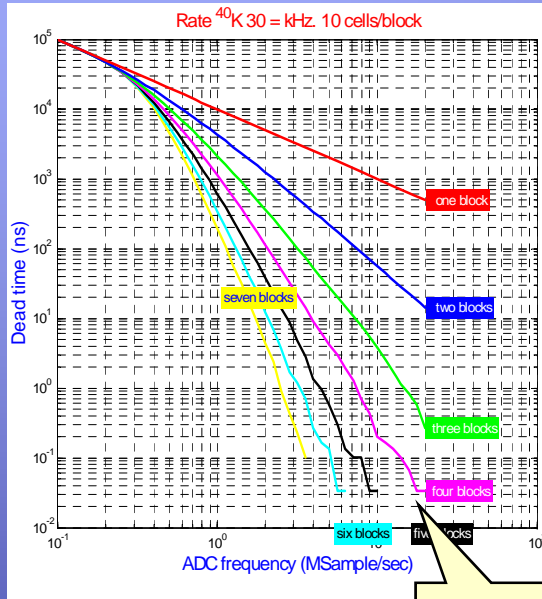
Lower ageing of PMT!

⁴⁰K Rate vs Readout frequency

30kHz

50kHz

500kHz



50 ps

Dead time vs. ADC freq.

100 ps

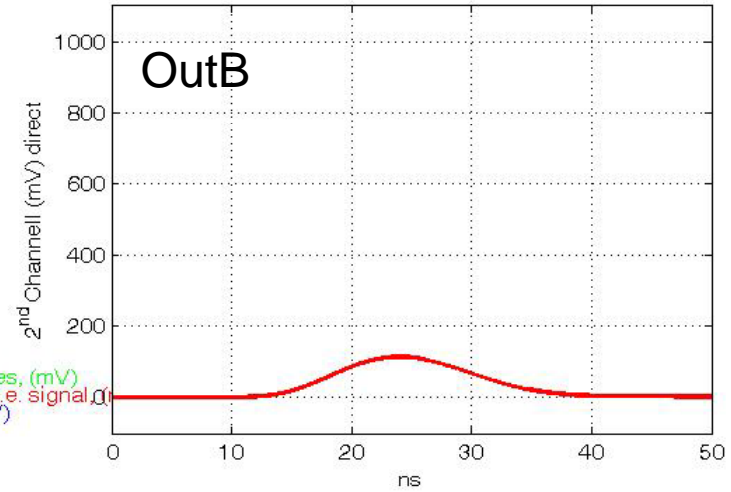
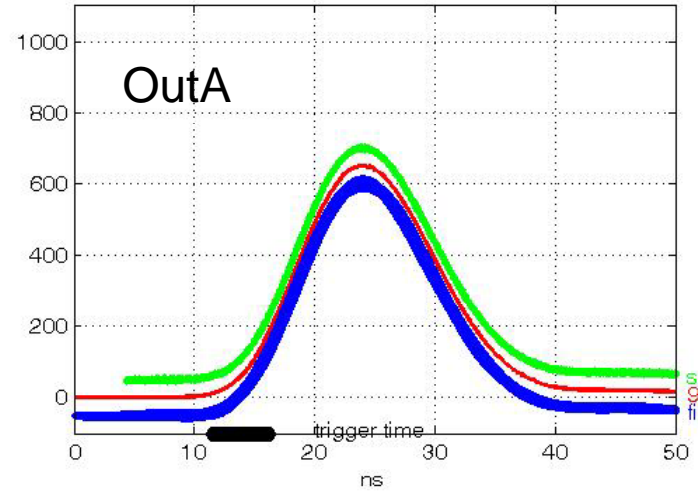
2 ns

We must use a buffer solution to limit dead time. A p.e. signal is long less than 40 ns. At 200Msample/sec we will use 10 cell blocks. We have simulated dead time vs block number for different ⁴⁰K rates.

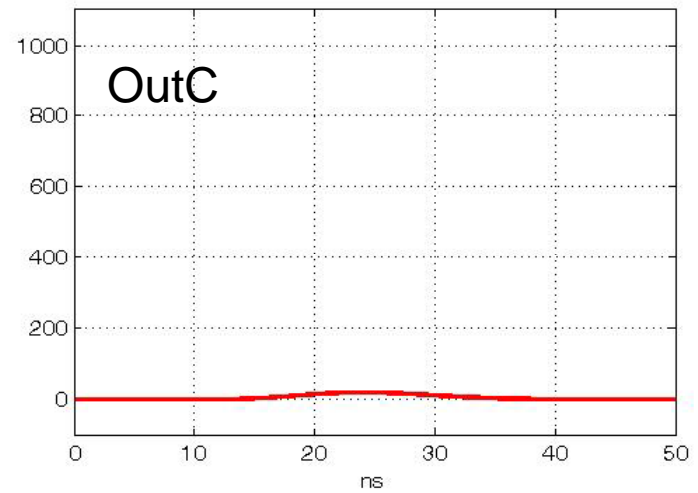
Four 10-cell block are able to limit dead time at reasonable dead time

10 p.e.

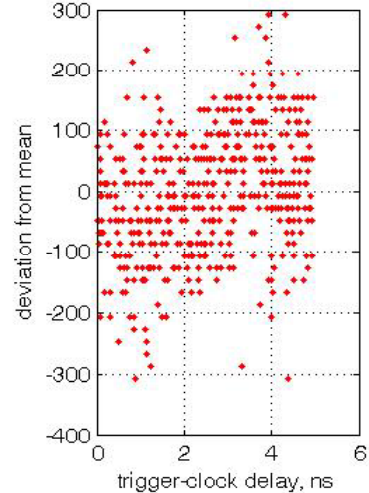
$G_{Pmt} \cdot 8 \cdot 10^6$; Ck, 5ns; j_t 100ps_{rms}; noise, 344 μ V_{rms}; P_{ed} 1.5mV_{rms}; ADC 10bit



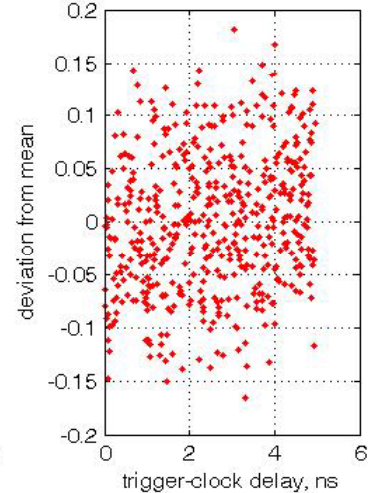
$G_{Pmt} \cdot 8 \cdot 10^6$; Ck, 5ns; j_t 100ps_{rms}; noise, 344 μ V_{rms}; P_{ed} 1.5mV_{rms}; ADC 10bit



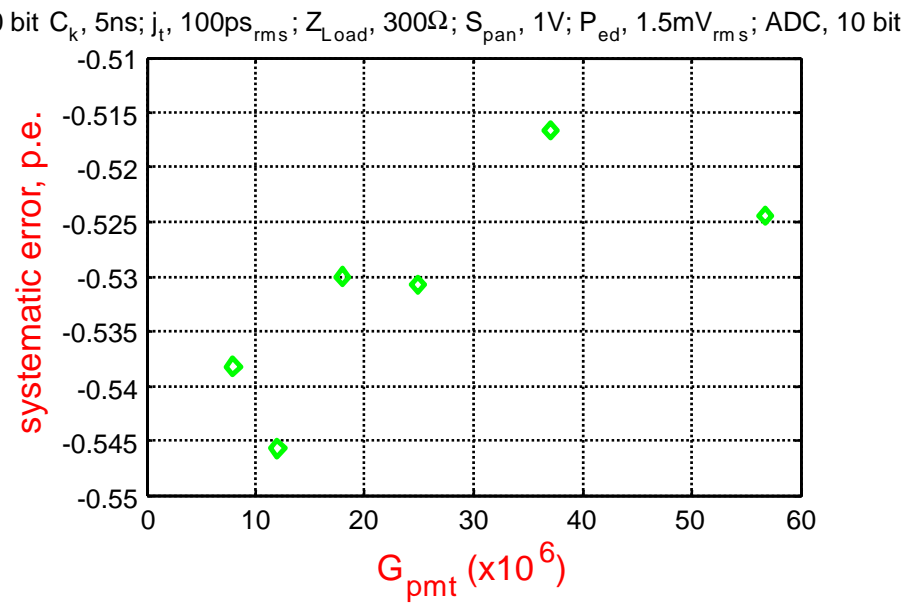
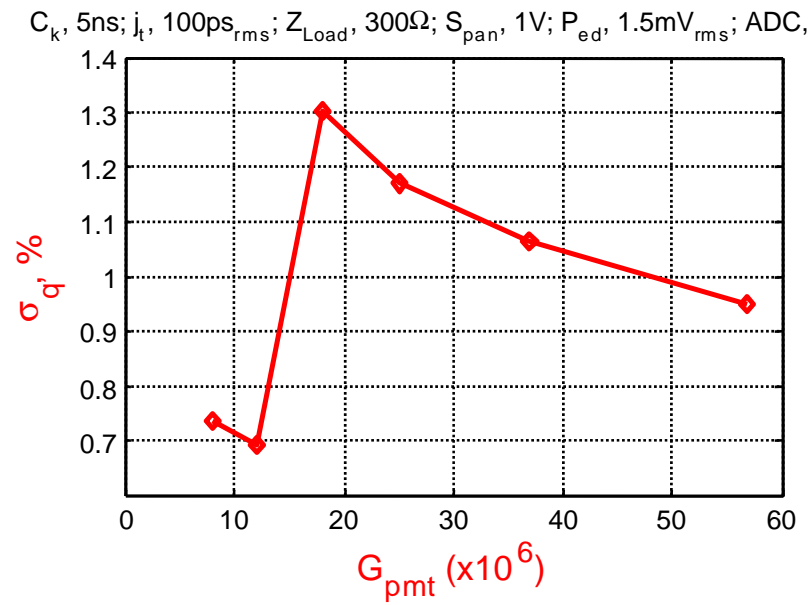
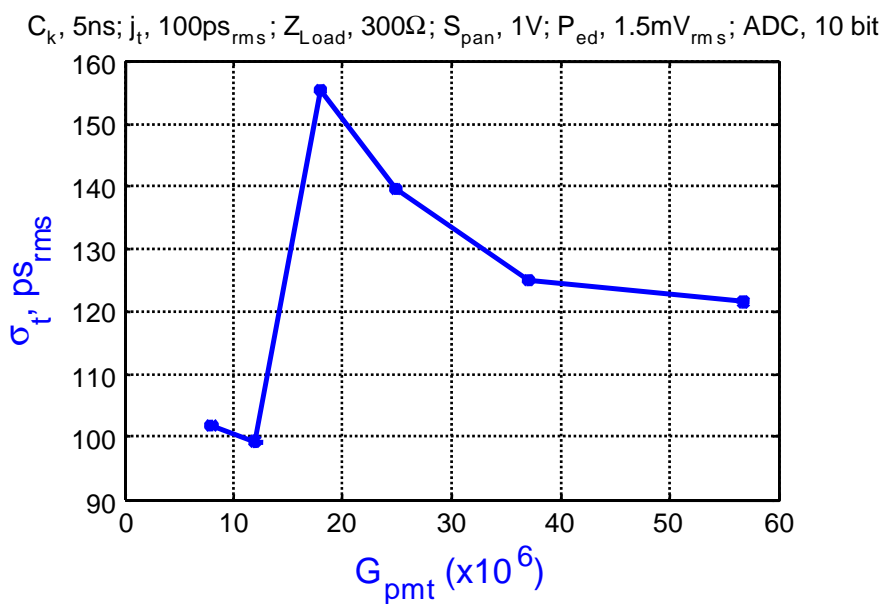
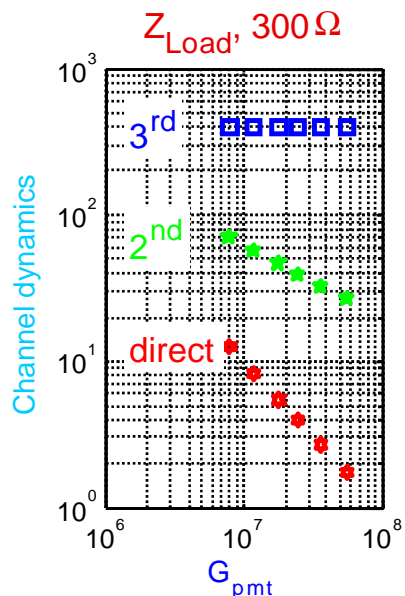
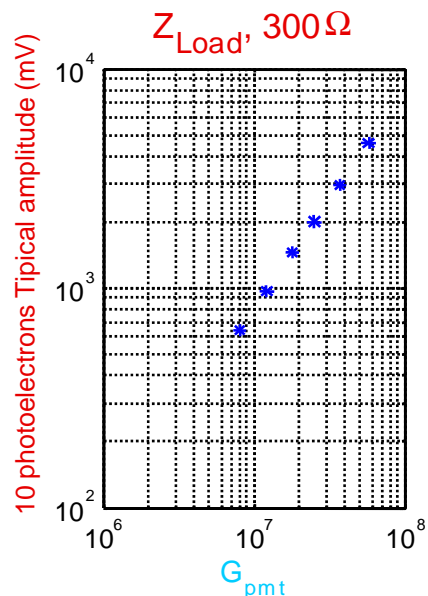
$P_t = 24.05$ ns; $\sigma_t = 102$ ps_{rms}



p.e. meas. = 9.32; $\sigma_e = 0.74$ %

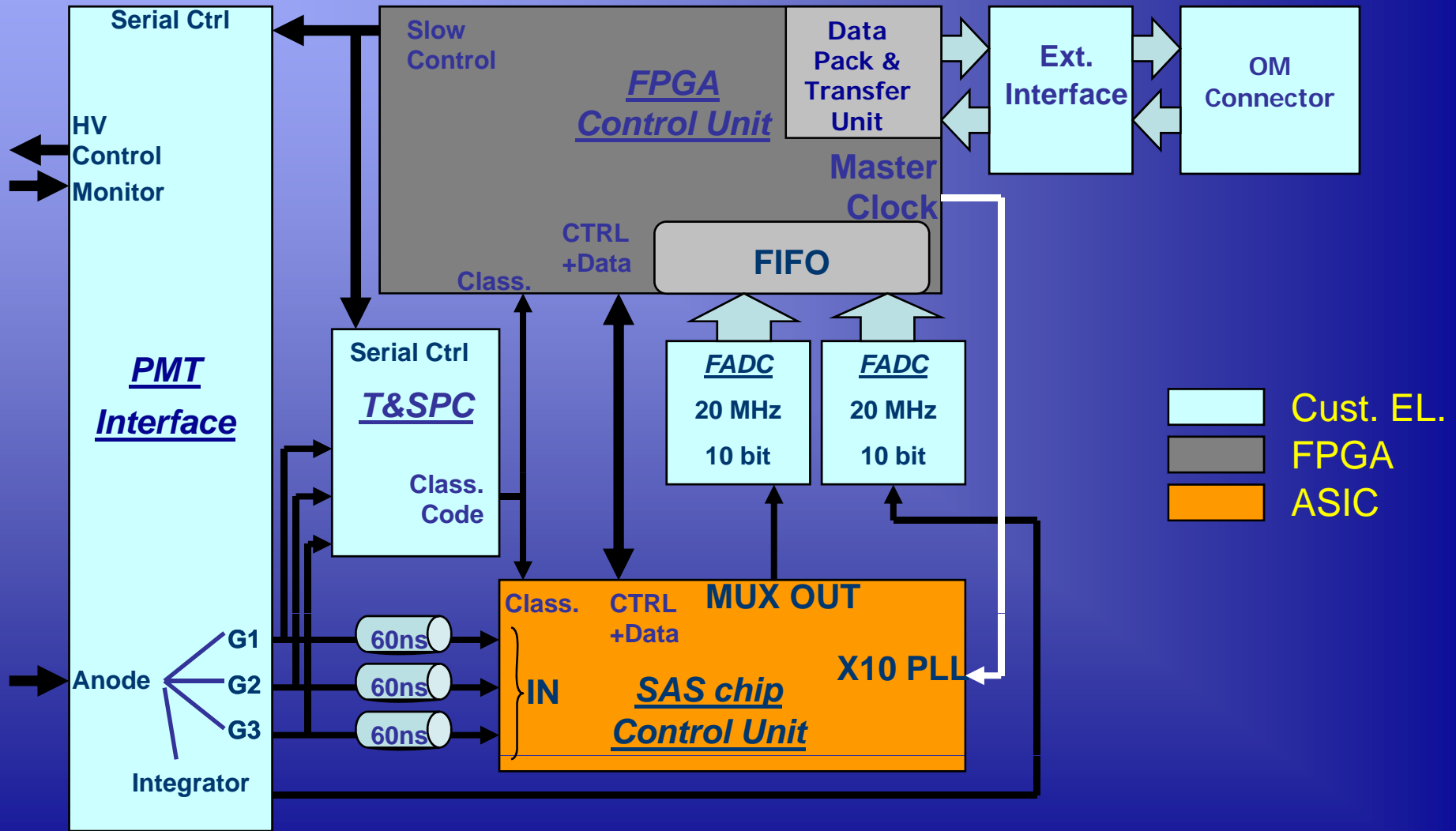


10 p.e.

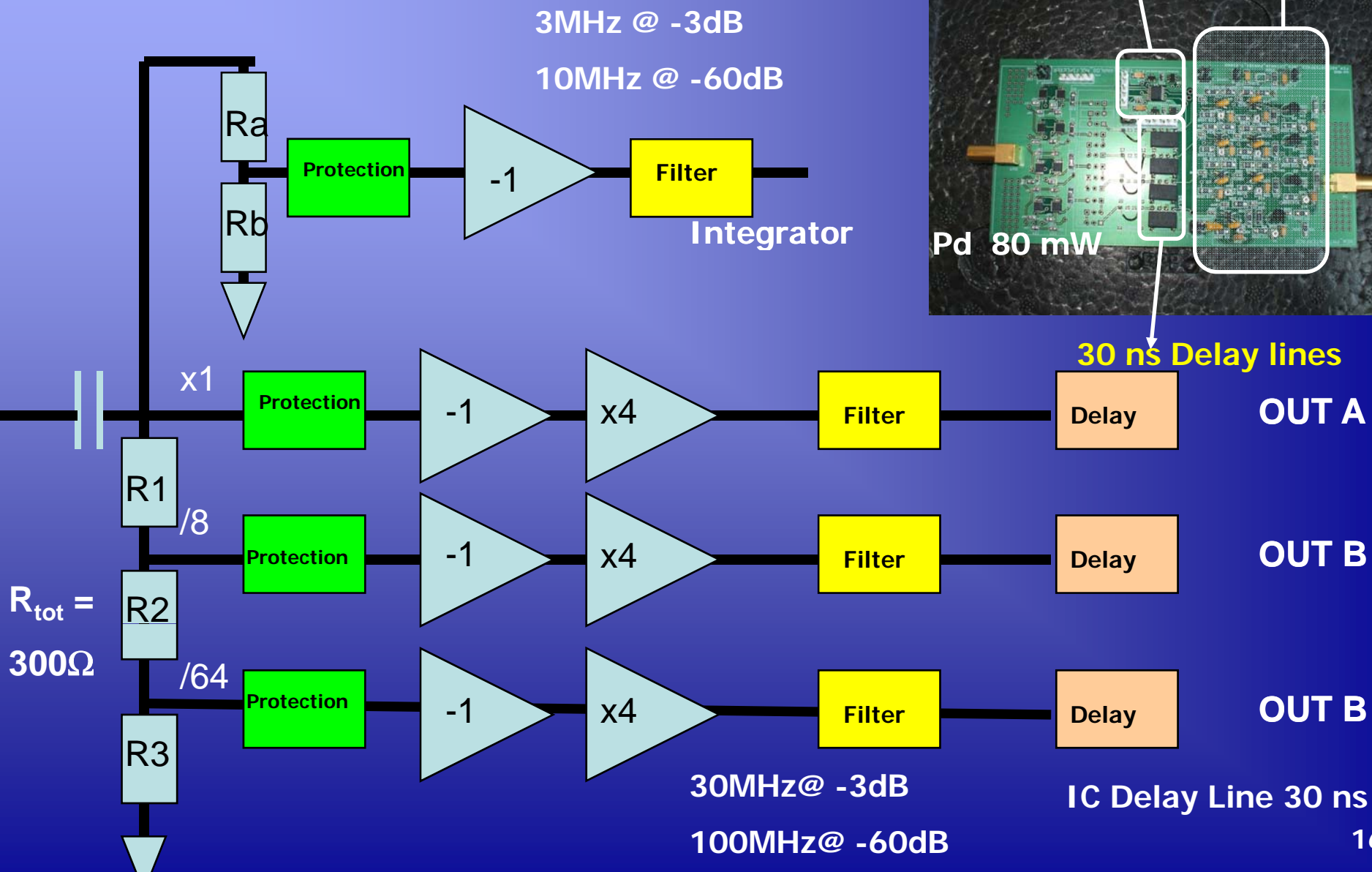


<i>General Requirements</i>	<i>Front End Specifications</i>
Low Power Dissipation	< 500 mW in each Optical Module (MO) -> Full-custom VLSI ASIC
Flexibility	Acquisition param. by Slow Control
High Dynamic Range	Linear Dynamic Range : > 512 PE / 60 ns 3 ranges: 8 PE / 60 ns; 64 PE / 60 ns; 512 PE / 60 ns Signal reconstruction up to 640ns Time and charge 12000 PE / 10 μ s
Minimum Dead Time	Dead Time < 1 ns Background 30 KHz (⁴⁰ K in 10'' PMT)
Optimal Resolution	Time resolution 200 ÷ 300 ps Charge resolution 2 ÷ 3 %
Low Cost	

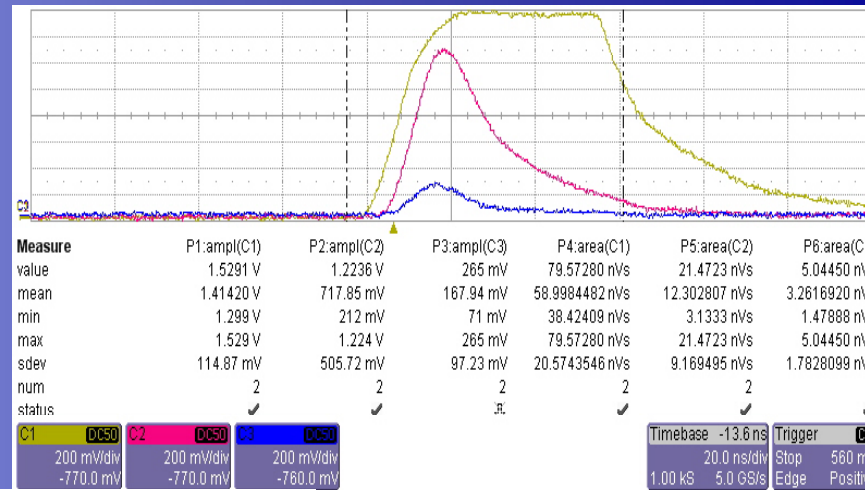
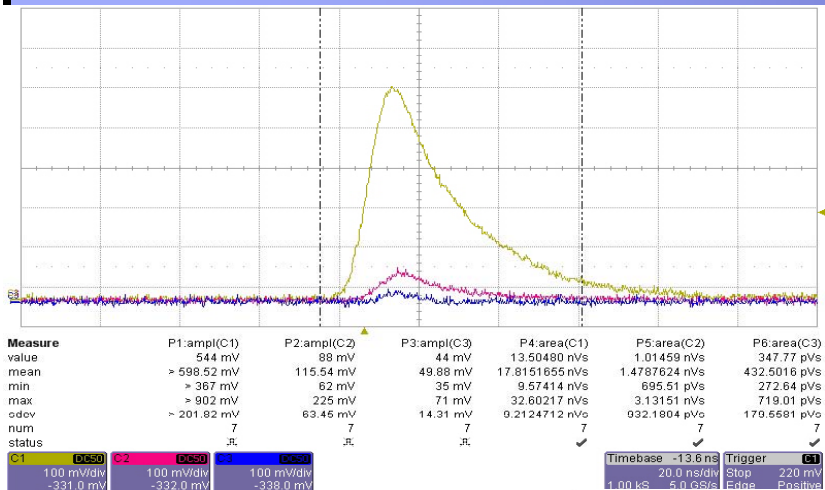
Optical Module Low Power Front-end Architecture



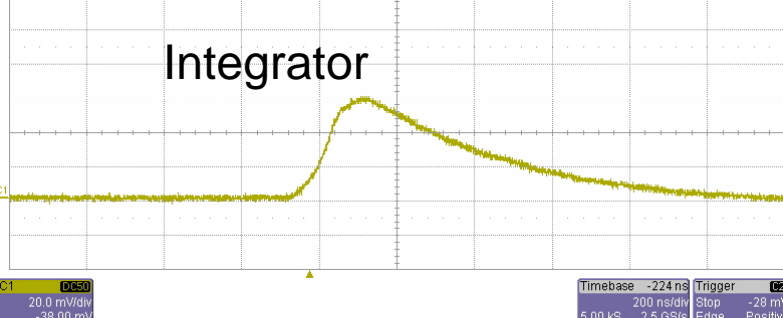
PMT Interface Block Diagram



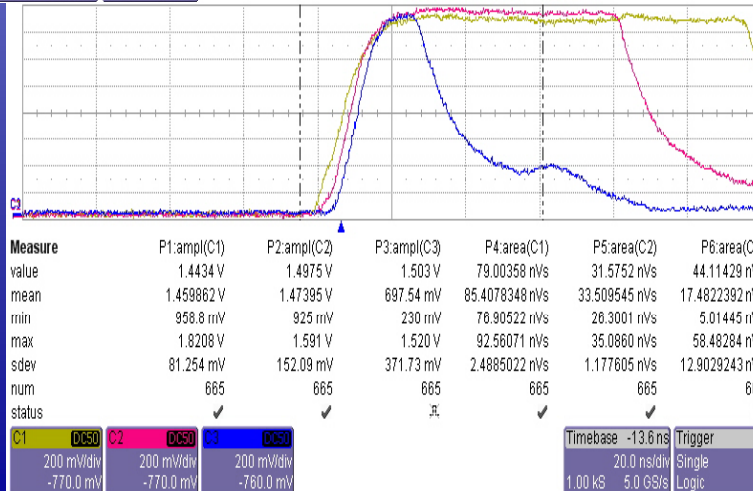
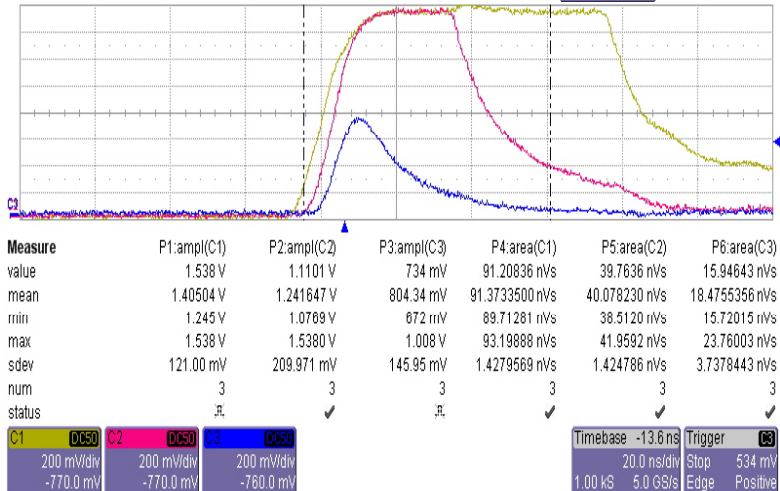
PMT interface - measurements



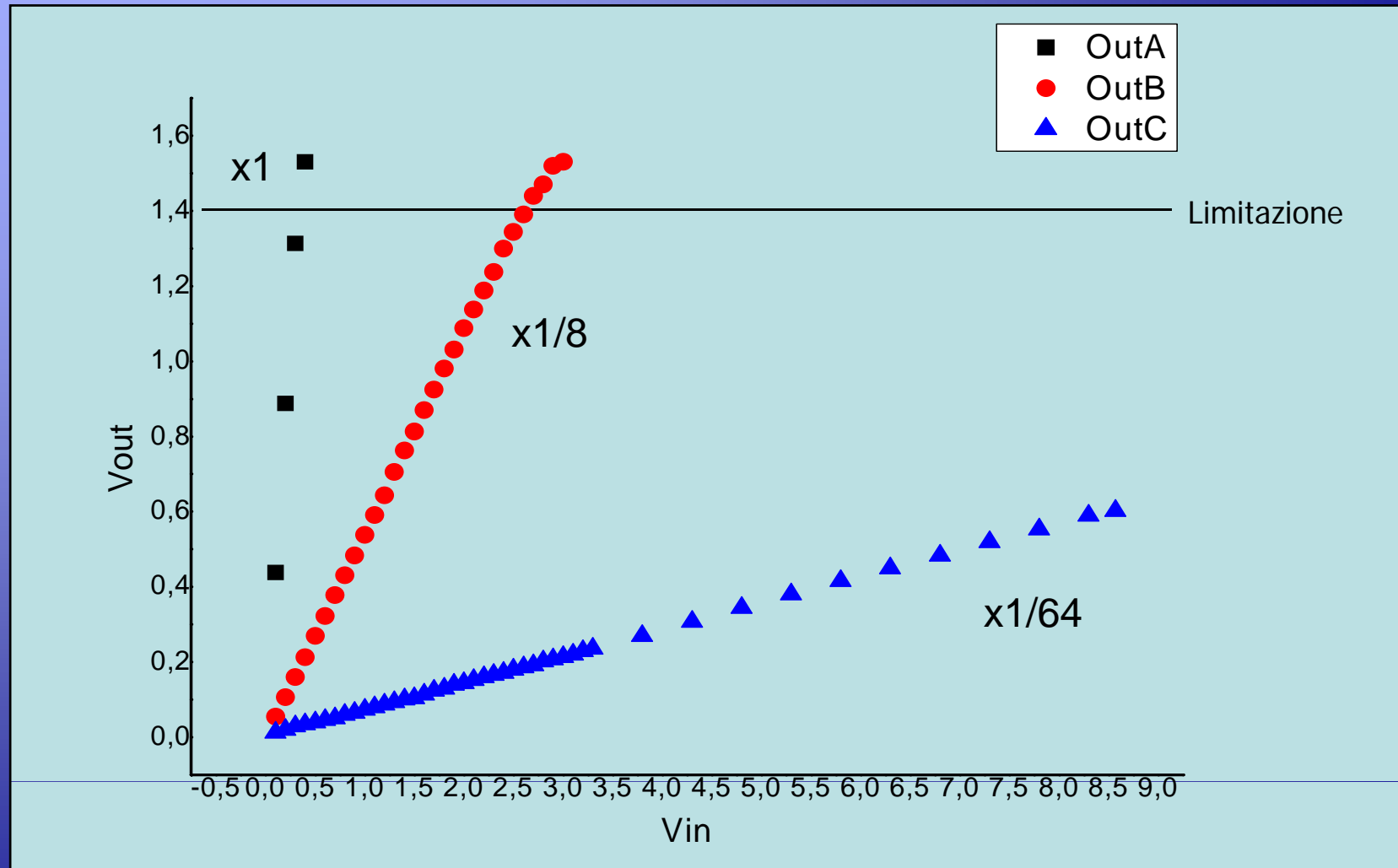
< 8 pe
64 pe ÷ 512 pe



8 pe ÷ 64 pe
> 512 pe



PMT interface - linearity



Test with $100\text{mV} \div 8,56\text{ V}$ equivalent to anode current pulse $333\mu\text{A} \div 28\text{mA}$ -> @ range $3\text{pe} \div 280\text{ pe}$ ($5 \cdot 10^6$, 300Ω)

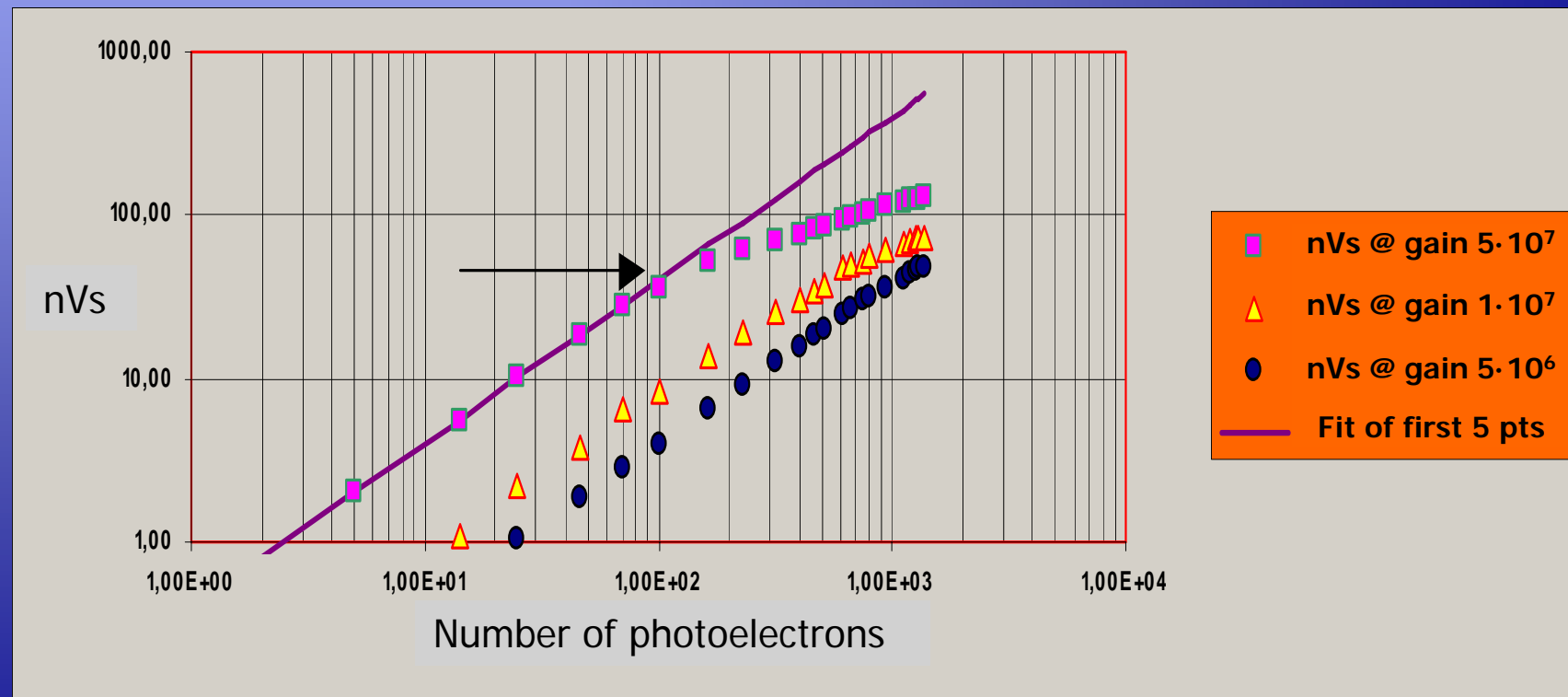
PMT saturation @ 1nC = about 1250 pe ($5 \cdot 10^6$, 300Ω)

PMT dynamic range VS Gain

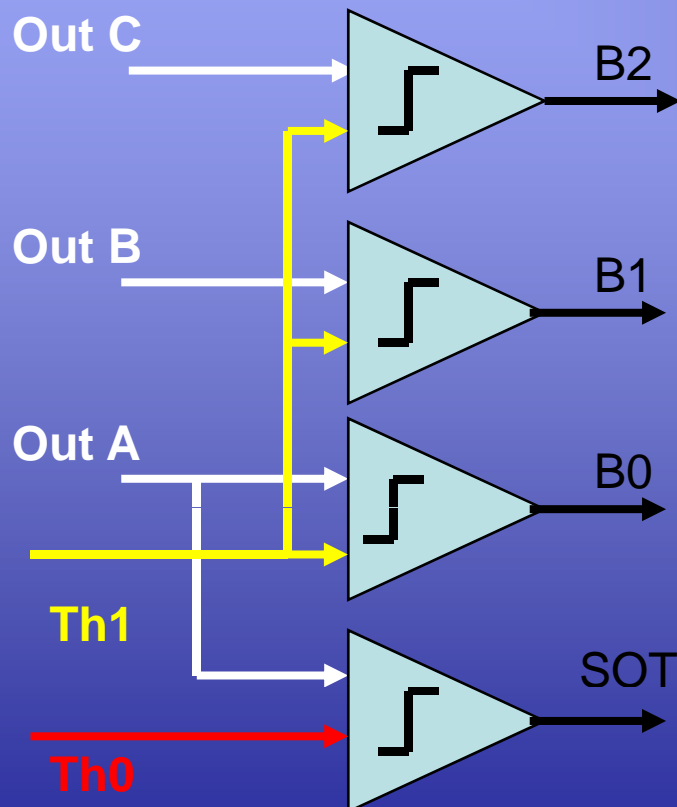
The effect of saturation seems to be determined by the anodic pulsed current and independent from the gain.

Limit Value of about 1 nC

120-150 p.e. @ gain $5 \cdot 10^7$



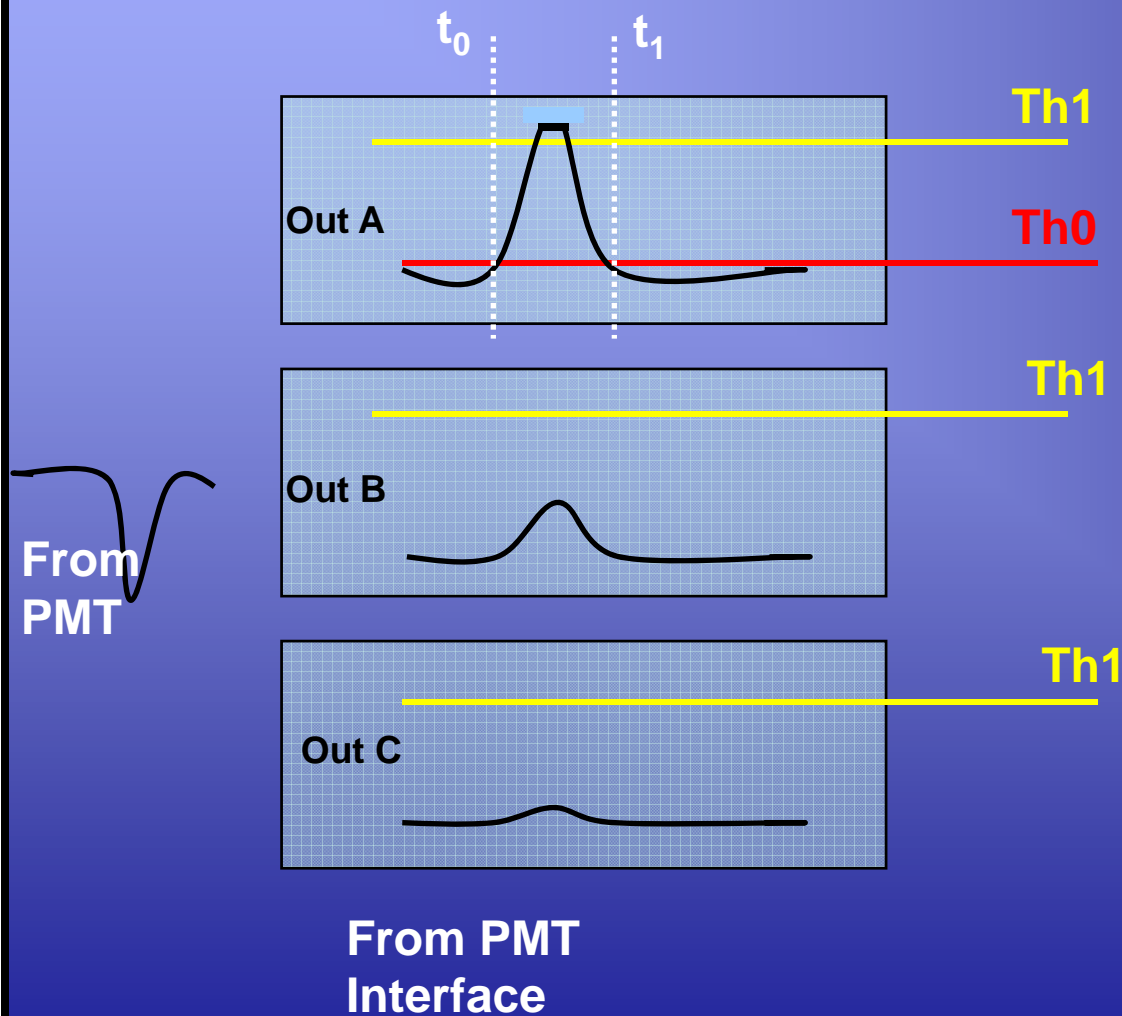
Trigger & Single Photon Classifier block diagram



Fast comparator
with hysteresis

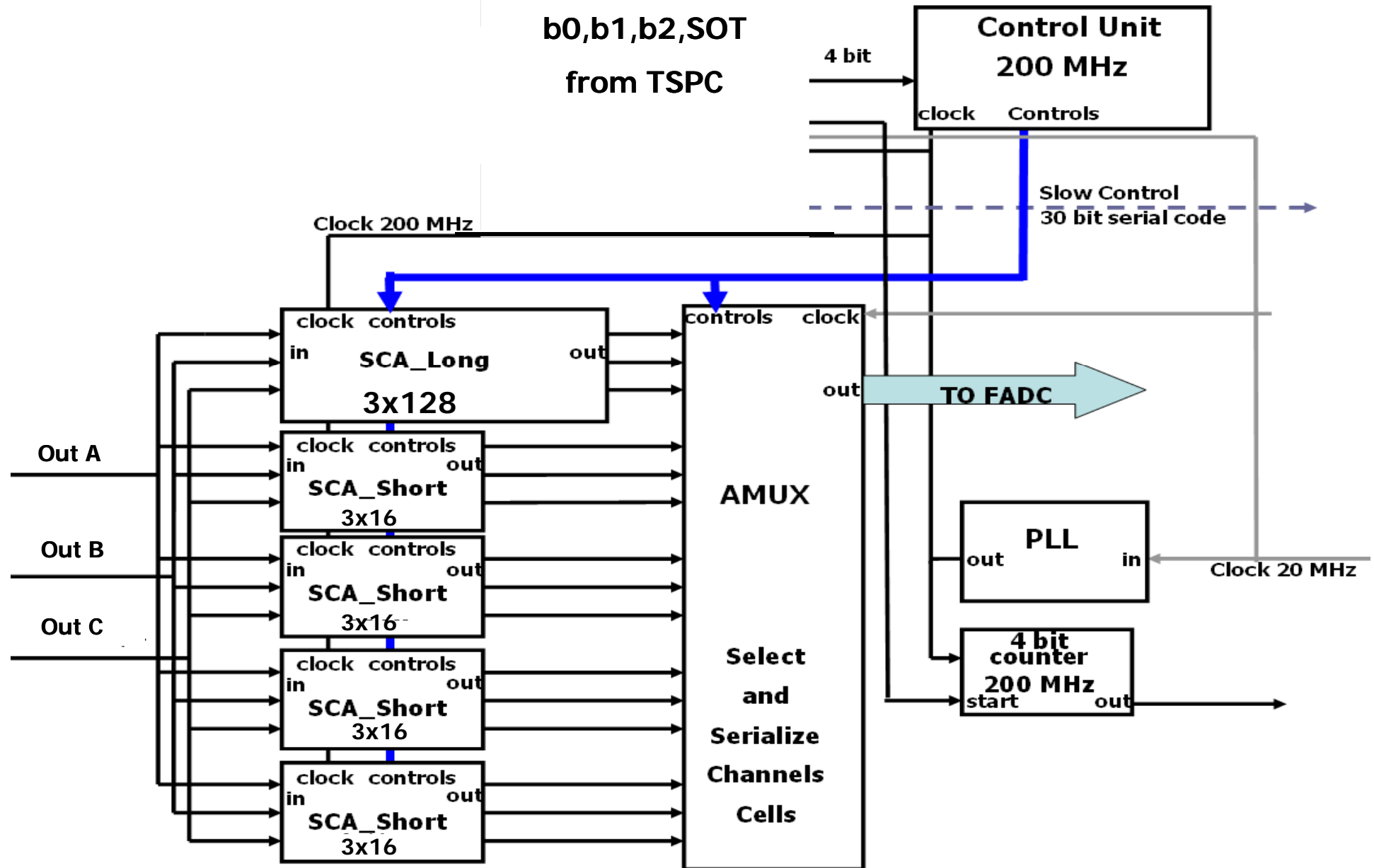
- B0, B1, B2 = PMT signal classification code
- SOT, Signal Over Threshold, twofold use:
 - Rising edge Trigger;
 - SOT width determines sampling mode (Short, Long, Integ.)
- Th0 e Th1 generated by 2 6-bit **DAC** serial code (Slow Control).
 - Th0 trigger threshold;
 - Th1 Out of range threshold.
- Asynchronous and always active.

An example...



- @ t_0 event trigger;
- $\Delta t = t_1 - t_0$ compared to Short length (60 ns);
- If bigger after a Short also a Long sampling of the signal.
- The classification code is:
 - $B0=1; B1=0; B2=0$.
- OutB samples will be converted!!

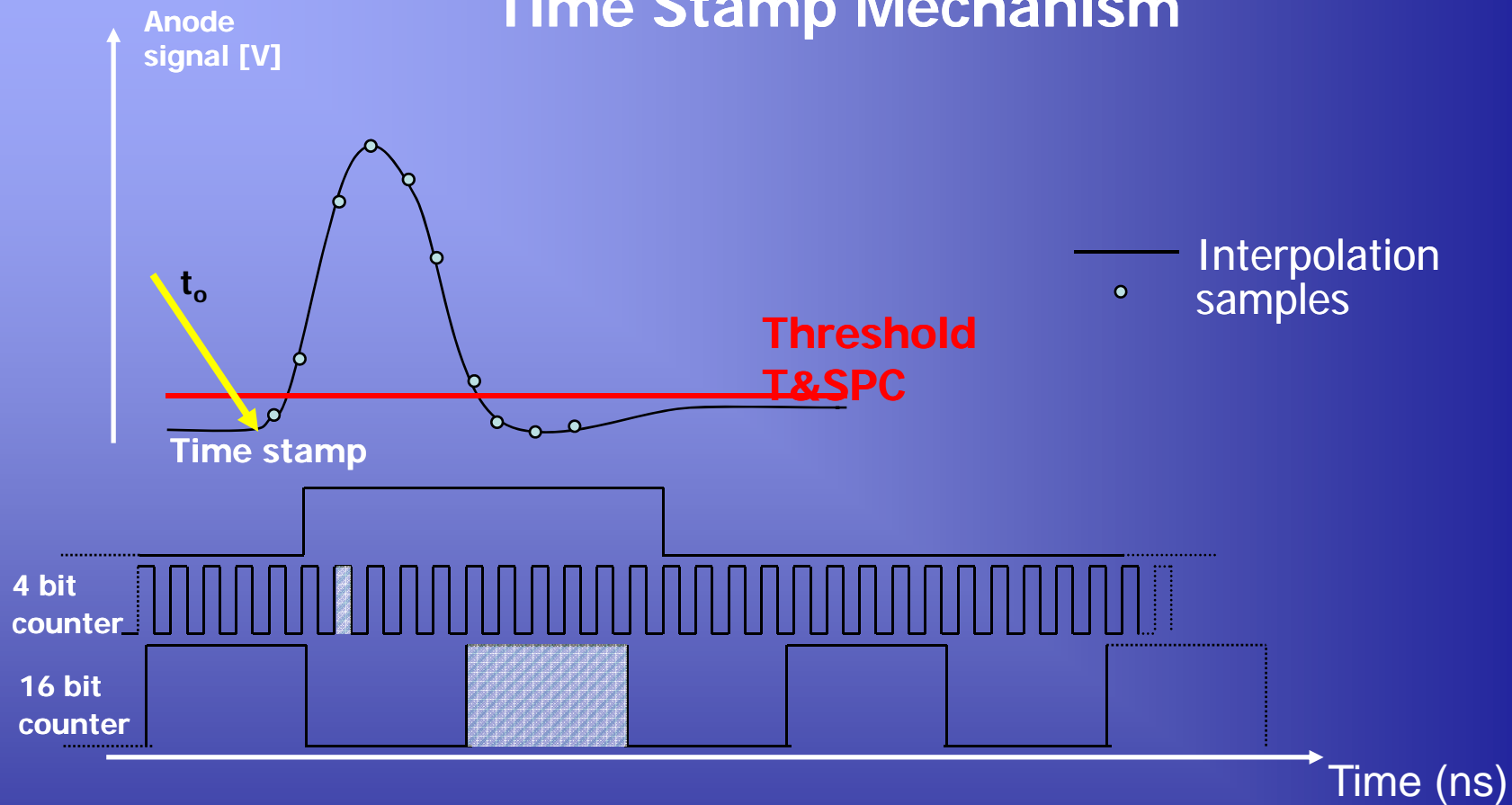
CHIP SAS - block diagram (Smart Autotriggering Sampler)



Sampling

- 3 sampling modes:
 - SAS_SHORT
 - o 4 independent memory banks: sampling @ START (T&SPC)
 - 3 channels 16 cells
 - 200 MHz sampling 20 MHz transfer
 - Serial transfer towards ADC
 - SAS_LONG
 - o T&SPC enabled: signal over Threshold more than 60 ns
 - 3 channels 128 cells
 - 200 MHz sampling 20 MHz transfer
 - Serial transfer towards ADC
 - FADC (external 10b 20 MHz ADC)
 - o T&SPC enabled: signal over Threshold more than 640ns
 - Integrated signal
 - 10 bit 20 MHz Flash ADC
 - 1 Ksample record length

Time Stamp Mechanism

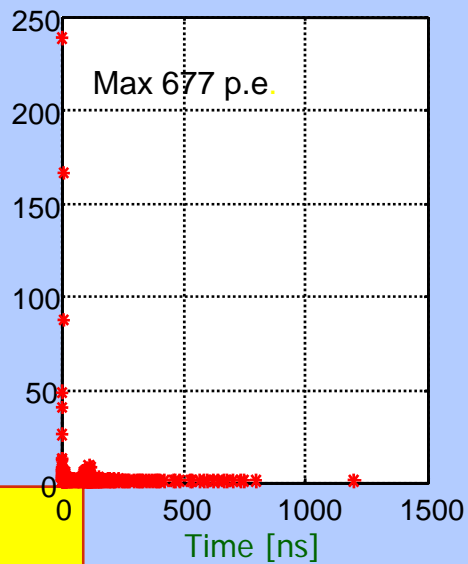


Time Stamp = 20 bit sent to data acquisition

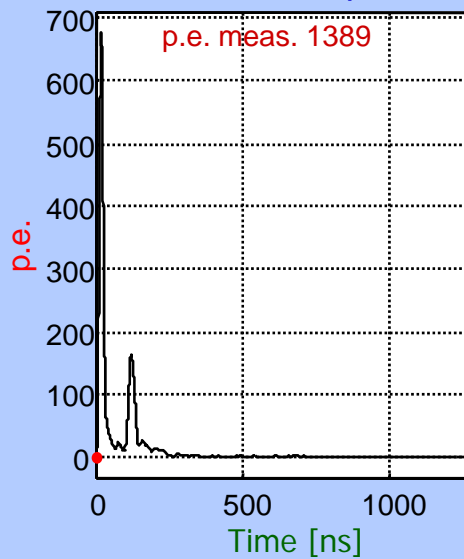
- One time stamp for sampler
- Dedicated FIFO

t_0 reconstructed offline

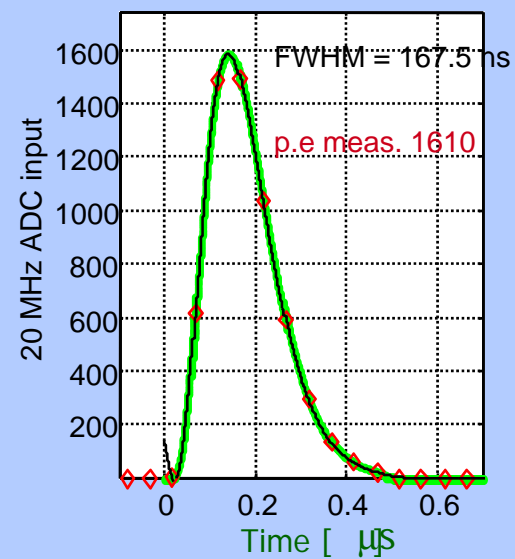
Event 362. PMT 364. SCA 1



total 1602 p.e.

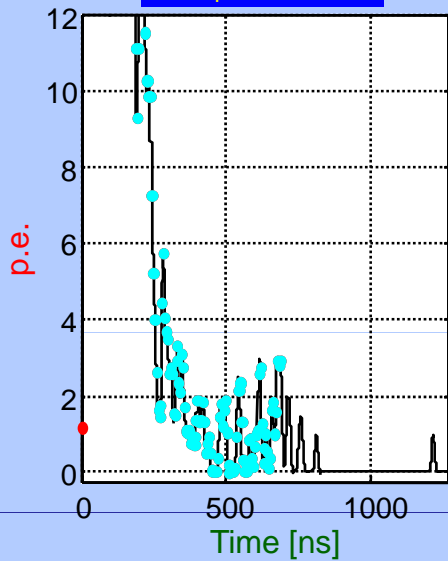


$\Delta Q/Q = 0.5\%$

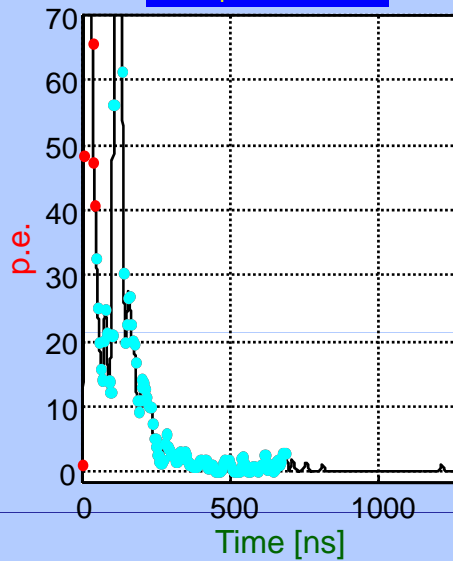


$G_{\text{pmt}} = 8 \cdot 10^6$
 $Z_L = 300 \Omega$

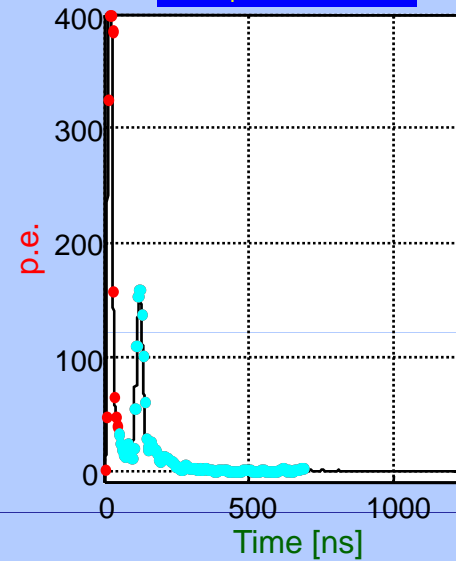
Ch1_{span} = 12 p.e.

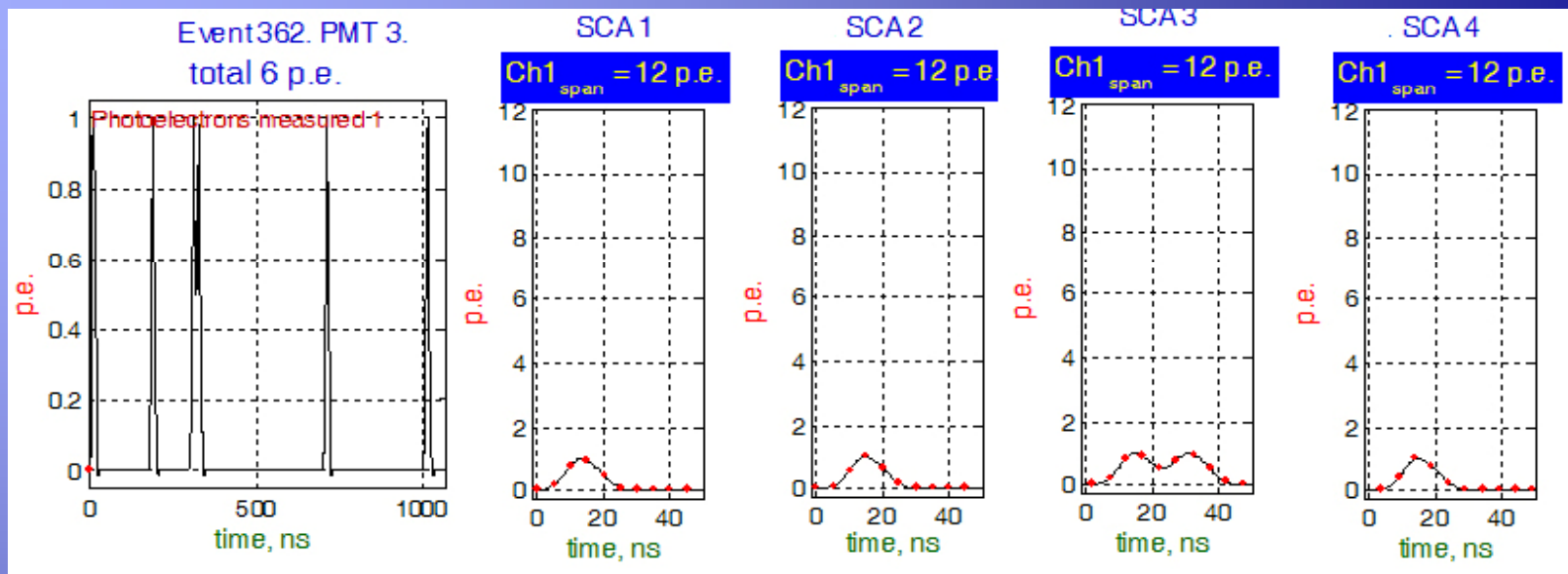


Ch1_{span} = 70 p.e.



Ch1_{span} = 400 p.e.





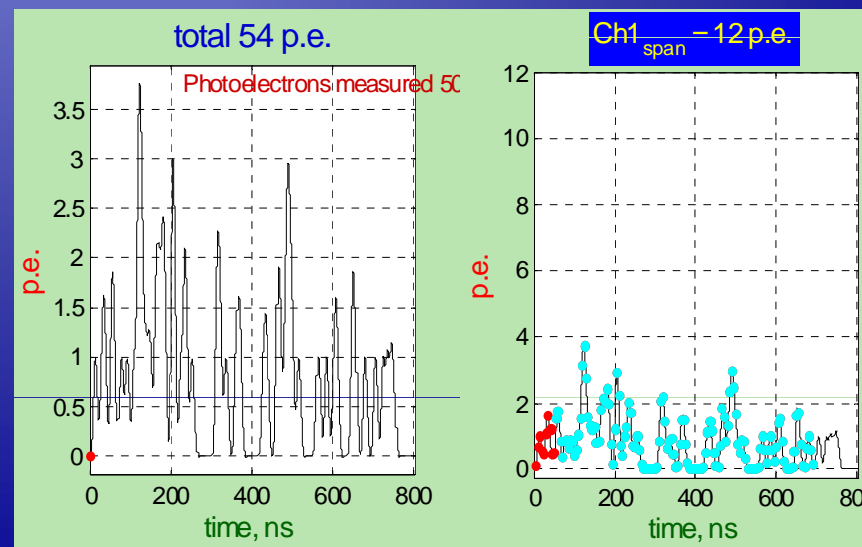
Very rare event -> 5 successive pulses @ more than 50 ns

4 events fully sampled- 1 lost

$$G_{\text{pmt}} = 8 \cdot 10^6;$$

$$Z_L = 300 \Omega$$

Structured signal ->
well reconstructed with 128
cells

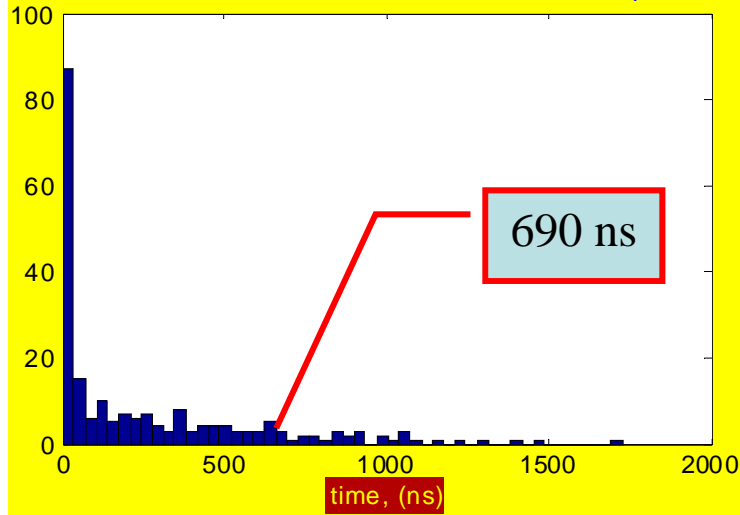


In this event we have 13097 p.e.

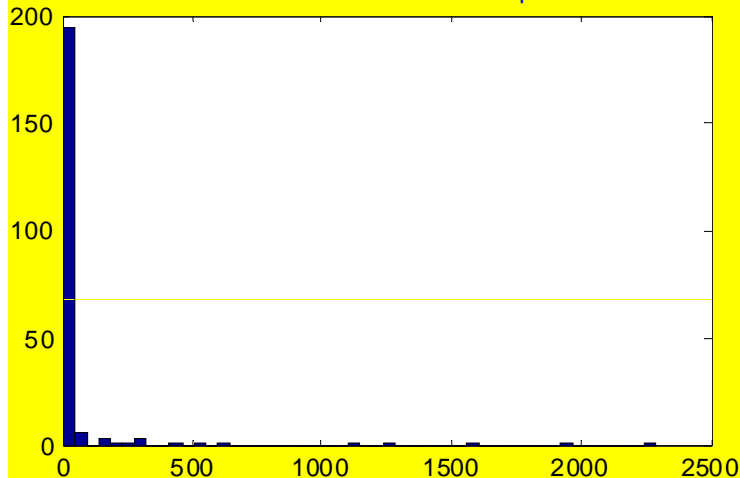
We are able to measure its charge using a 128 SCA (640ns) with an error < 0.26%

$$G_{\text{pmt}}=8 \cdot 10^6; Z_L=300\Omega$$

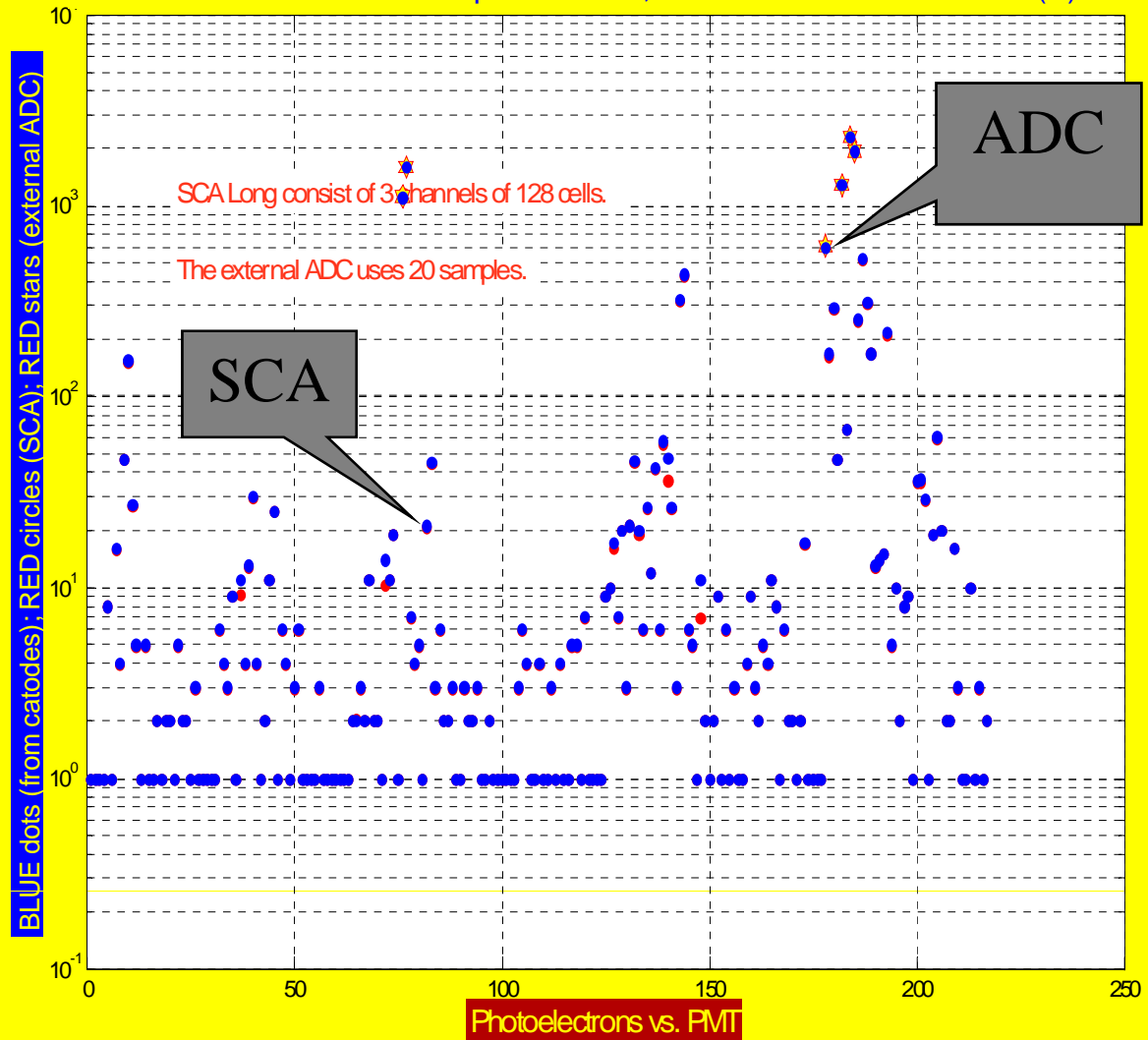
Event n° 290. Intervals between first and last pulse



Event n° 290. Photoelectrons from photocatodes



Event n° 290. SAS measures 4262 photoelectrons, ADC 8850. Sum 13112 of 13146(%) -0.26



Conclusions

- The front end electronics architecture has been defined and under design;
- PMT interface and TSPC ready;
- Master Control Unit (FPGA) ready;
 - See F. Giorgi talk
- ASIC ready soon (beginning of 2008);
- Test in NEMO phase 2

Thank You